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Patent 14402-0070

Serial No. 09/974,659 Applicant: Kurozumi et al.. Group Art Unit: 2877

CLAIM AMENDMENTS

- (Currently Amended) A light scattering particle size distribution measuring apparatus, comprising:
 - a light source capable of emitting laser light;
 - a light shutter modulating said laser light;
 - a beam expander expanding said laser light;
 - a material cell containing a material sample;
 - a condensor lens capable of focusing transmitted and scattered light;
 - a photodetector capable of receiving said scattered and transmitted light;
- at least one optical axis adjustment mechanism capable of automatically aligning and maintaining a central position of said photodetector with a central position of the said light source;
- a multiplexer in communication with said photodetector and said optical axis adjustment mechanism; and
- a CPU in communication with said multiplexer and a personal computer, said CPU capable of providing control signals to said at least one optical axis adjustment mechanism based on a signal received from said photodetector.
- (Currently Amended) The apparatus of claim 1, further comprising a mirror; said mirror positioned between said light source and said light shutter.
- 3. (Currently Amended) The apparatus of claim 1, further comprising a first cuneal prisms and a second cuneal prism, wherein said first and second cuneal prisms positioned between said beam expander and said material cell.



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- 4. (Originally filed) The apparatus of claim 1 wherein said optical axis adjustment mechanism comprises an X-Y optical positioning stage.
- 5. (Currently Amended) The apparatus of claim 1 wherein said optical axis adjustment mechanism <u>is in communication</u> with at least one device selected from the group consisting of said light source, said mirror, said beam expander, said condensor lens, and said photodetector.
- 6. (Originally filed) A light scattering particle size distribution measuring apparatus, which irradiates a sample with light from a light source, detects the resulting scattered light from the sample by a photodetector, and measures the size distribution of particles in the sample on the basis of a scattered light intensity pattern obtained, comprising a mechanism capable of automatically adjusting the central positions of the light source and the photodetector in a state most suitable for measuring by always monitoring quantity of light antecedent to irradiating a sample and quantity of light on a photodetector after Irradiating a sample and adjusting a position of a light source, a photodetector or an optical device between the light source and the photodetector.
- 7. (Originally filed) A light scattering particle size distribution measuring apparatus, which irradiates a sample with light from a light source, detects the resulting scattered light from the sample by a photodetector, and measures the size distribution of particles in the sample on the basis of a scattered light intensity pattern obtained, comprising an optical axis adjustment mechanism capable of holding control data antecedent to a decrease of a quantity of light when the quantity of light on a photodetector is significantly lowered compared with a quantity of light antecedent to irradiating a sample by always monitoring the quantity of light antecedent to irradiating a sample and the quantity of light on a photodetector.
- 8. (Currently Amended) A method of using the scattering of light to measure the particle size distribution within a sample, comprising;

Irradiating a sample with light from a light source;

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detecting a resulting scattered light from the sample by a photodetector;

monitoring a central position of the light source and the photodetector;

monitoring a quantity of light antecedent to irradiating the sample and a quantity of light on the photodetector.

measuring a size distribution of particles in the sample on the basis of a scattering light intensity pattern-obtained; and

storing and retrieving an optimal position in a range of a quantity of light on a photodetector.

9. (Currently Amended) A method of using the scattering of light to measure the particle size distribution within a sample, comprising:

irradiating a sample with light from a light source;

detecting a resulting scattered light from the sample by a photodetector;

monitoring a central position of the light source and the photodetector;

monitoring a quantity of light antecedent to irradiating the sample and a quantity of light on the photodetector;

measuring a size distribution of particles in the sample on the basis of a scattered light intensity pattern-obtained; and

aligning and maintaining a central position of said photodetector with a central position of [the]said light source with an automatic adjustment mechanism.

10. (New) A light scattering particle size distribution measuring apparatus, comprising:

a light source capable of emitting laser light;



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Carry

- a light shutter modulating said laser light;
- a beam expander expanding said laser light;
- a material cell containing a material sample;
- a condensor lens capable of focusing transmitted and scattered light:
- a photodetector capable of receiving said scattered and transmitted light;
- at least one optical axis adjustment mechanism capable of automatically aligning and maintaining a central position of said photodetector with a central position of the said light source and configured to always monitor a quantity of light antecedent to irradiating the material sample and a quantity of light on the photodetector, wherein the optical axis adjustment mechanism comprises an X-Y optical positioning stage-:
- a multiplexer in communication with said photodetector and said optical axis adjustment mechanism; and
- a CPU in communication with said multiplexer and a personal computer, said CPU capable of providing control signals to said at least one optical axis adjustment mechanism based on a signal received from said photodetector.